Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/717,913	ICHIMURA ET AL.
Examiner	Art Unit
David E. Bochna	3679

	SEARCHED				
Class	Subclass	Date	Examiner		
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Updated the previous search ເ	11/17/2005	DB		
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